

L Number	Hits	Search Text	DB	Time stamp
2	60	surface adj2 (map\$3 or scan) same (defect or feature) and steel	USPAT; US-PGPUB	2004/08/31 13:24
3	306	surface adj2 (map\$3 or scan) and (defect or feature) same (correlat\$3 or classif\$7)	USPAT; US-PGPUB	2004/08/31 13:25
4	82	surface adj2 (map\$3 or scan) and (defect or feature) same (correlat\$3 or classif\$7) and (sheet or elongate)	USPAT; US-PGPUB	2004/08/31 14:05
18	0	surface adj2 (map\$3 or scan) same (correlat\$3 or classif\$7)	USPAT; US-PGPUB	2004/08/31 14:05
19	0	same production adj2 data same rules	USPAT; US-PGPUB	2004/08/31 14:12
20	2	surface adj2 (map\$3 or scan) same (correlat\$3 or classif\$7) same production adj2 data and rules	USPAT; US-PGPUB	2004/08/31 14:13
21	828	surface adj2 (map\$3 or scan) same production adj2 data	USPAT; US-PGPUB	2004/08/31 14:13
22	154	surface adj2 (map\$3 or scan) and feedback	USPAT; US-PGPUB	2004/08/31 14:13
23	63	surface adj2 (map\$3 or scan) and feedback and sheet	USPAT; US-PGPUB	2004/08/31 14:40
26	14	surface adj2 (map\$3 or scan) and feedback and sheet and (correlat\$3 or classif\$7)	USPAT; US-PGPUB	2004/08/31 15:00
31	0	surface adj2 (map\$3 or scan) same (correlat\$3 or classif\$7) and feedback	USPAT; US-PGPUB	2004/08/31 15:00
32	55	product near4 (correlat\$3 or classif\$7) near4 process same feedback	USPAT; US-PGPUB	2004/08/31 15:15
33	728	product near4 (correlat\$3 or classif\$7) near4 process and feedback	USPAT; US-PGPUB	2004/08/31 15:05
34	20	defect near2 classification	USPAT; US-PGPUB	2004/08/31 15:05
35	0	defect near2 classification same feedback	USPAT; US-PGPUB	2004/08/31 15:16
36	0	product near2 data same (correlat\$3 or classif\$7) same process near2 data same feed adj2 back	USPAT; US-PGPUB	2004/08/31 15:16
37	9	product near2 data same correlat\$3 same process near2 data same (feed or fed) adj2 back	USPAT; US-PGPUB	2004/08/31 15:18
38	83	product same correlat\$3 same process same data same (feed or fed) adj2 back	USPAT; US-PGPUB	2004/08/31 15:23
39	94	product same correlat\$3 same process same data and (feed or fed) adj2 back	USPAT; US-PGPUB	2004/08/31 15:30
40	46	(sheet or elongate) same (manufactur\$3 or process\$3) and monitor same data same feedback same control	USPAT; US-PGPUB	2004/08/31 15:42
44	15	steel same surface same (manufactur\$3 or process\$3) and monitor same data same feedback same control	USPAT; US-PGPUB	2004/08/31 15:43
-	619	process near2 data same correlat\$3 same defect and feedback	USPAT; US-PGPUB	2004/02/24 11:21
-	4	700/109,110,148-156.ccls.	USPAT; US-PGPUB	2004/02/24 11:39
-	3	rolling adj2 mill same (steel or metal) same surface same (monitor or inspect)	USPAT; US-PGPUB	2004/08/30 13:54
-	6	surface adj2 defect adj2 map	USPAT; US-PGPUB	2003/09/30 15:44
-	6	surface adj2 defect adj2 distribution	USPAT; US-PGPUB	2003/10/01 11:30
-	430	surface adj2 defect same entropy	USPAT; US-PGPUB	2003/10/01 11:37
-	2	surface adj2 defect same (correlate or classify or group)	USPAT; US-PGPUB	2003/09/30 15:48
-	1	surface adj2 defect same (correlate or classify or group) same filter	USPAT; US-PGPUB	2003/09/30 15:48
-	3	surface adj2 defect same (correlate or classify or group) and entropy	USPAT; US-PGPUB	2003/10/01 13:23
-	29	surface adj2 defect same (correlate or classify or group) same trend	USPAT; US-PGPUB	2003/10/01 11:30
-	387	surface adj2 defect and entropy	USPAT; US-PGPUB	2003/10/01 11:42
-	275	surface adj2 defect same group	USPAT; US-PGPUB	2003/10/01 11:38
-		surface adj2 defect same group not (semiconductor or wafer)	USPAT; US-PGPUB	

-	3	surface adj2 defect same detect same group not (semiconductor or wafer)	USPAT; US-PGPUB	2003/10/01 11:40
-	7	surface adj2 defect same (detect or identify) same group\$3 not (semiconductor or wafer)	USPAT; US-PGPUB	2003/10/01 11:40
-	36	surface adj2 defect same trend	USPAT; US-PGPUB	2003/10/01 13:27
-	2	surface adj2 defect same spc	USPAT; US-PGPUB	2003/10/01 13:28
-	18	surface adj2 defect and spc	USPAT; US-PGPUB	2003/10/01 13:28
-	0	10/030238	USPAT; US-PGPUB	2003/10/01 14:30
-	51	700/109,110,148-156.ccls. and @pd >= "20030930"	USPAT; US-PGPUB	2004/08/30 11:05
-	5	rolling adj2 mill same (steel or metal) same surface same (monitor or inspect)	USPAT; US-PGPUB	2004/02/24 11:41
-	107	(steel or metal) same surface same (monitor or inspect) same camera	USPAT; US-PGPUB	2004/02/24 11:42
-	381	(steel or metal) same surface same (monitor or inspect) same (camera or optical)	USPAT; US-PGPUB	2004/02/24 11:43
-	40	(steel or metal) same surface near2 (monitor or inspect) same (camera or optical)	USPAT; US-PGPUB	2004/02/24 13:19
-	0	(sheet or steel or metal) adj2 surface near2 (monitor or inspect) near2 camera	USPAT; US-PGPUB	2004/02/24 13:20
-	56	surface near2 (monitor or inspect) near2 camera	USPAT; US-PGPUB	2004/02/24 13:31
-	72	700/109,110,148-156.ccls. and @pd >= "20040223"	USPAT; US-PGPUB	2004/08/30 11:05
-	9	surface adj2 defect adj2 map\$3	USPAT; US-PGPUB	2004/08/30 13:59
-	1873	surface adj2 map\$3	USPAT; US-PGPUB	2004/08/30 14:00
-	352	surface adj2 map\$3 and classif\$7	USPAT; US-PGPUB	2004/08/30 14:00
-	32	surface adj2 map\$3 and classif\$7 same (correlat\$5 or rule)	USPAT; US-PGPUB	2004/08/30 14:30
-	191	surface adj2 map\$3 and steel	USPAT; US-PGPUB	2004/08/30 15:12
-	10	surface adj2 map\$3 same steel	USPAT; US-PGPUB	2004/08/30 14:31
-	5	surface adj2 map\$3 same defect and steel	USPAT; US-PGPUB	2004/08/31 13:11
-	275	surface adj2 map\$3 same (defect or feature)	USPAT; US-PGPUB	2004/08/30 15:21